

FEATURES

Analog I/O

6-Channel 14-bit or 12-bit ADC

Single ended and differential inputs

Programmable data rate up to 842 kSPS

On-Chip Voltage Reference and Temperature Sensor

Power

Supply Range: 2.2 V to 3.6 V

Power Consumption

680 nA, in power down mode, non-retained state

1.6 µA, in power down mode, processor memory and transceiver memory retained

190 µA / MHz, Cortex in Active mode

12.8 mA transceiver in receive mode, Cortex in power down mode

9 mA to 32 mA transceiver in transmit mode, Cortex in power down mode

RF Transceiver

Frequency bands

862 MHz to 928 MHz

431 MHz to 464 MHz

Multiple Configurations supported

Receiver sensitivity (BER)

-107.5 dBm at 38.4 kbps, 2FSK

Single ended and differential PA

Low External BOM

Microcontroller

ARM Cortex™-M3 32-bit processor

Serial Wire download and debug

External Watch crystal for wakeup timer

16 MHz internal Oscillator with 8-way Programmable Divider

Memory

128 k Bytes /64 k Bytes Flash/EE Memory, 16 k Bytes /8 k Bytes SRAM

20000 cycle Flash/EE endurance

10 year Flash/EE retention

In-circuit download via Serial Wire and UART

On-Chip Peripherals

UART, I²C and SPI Serial I/O

28-Pin GPIO Port

2 General Purpose Timers

Wake-up Timer

Watchdog Timer

8-Channel PWM

Packages and Temperature Range

64 lead LFCSP (9mm x 9mm) package -40°C to 85°C

Tools

Low-Cost Development System

Third-Party Compiler and emulator tool Support

APPLICATIONS

Battery powered wireless sensor

Medical telemetry systems

Industrial and home automation

Asset tracking

Security systems (access systems)

Health and fitness applications

FUNCTIONAL BLOCK DIAGRAM

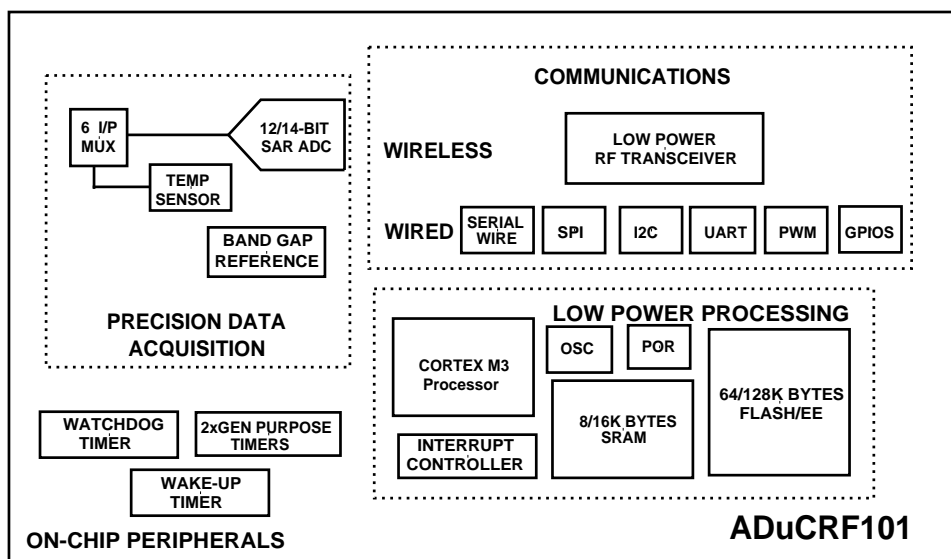


Figure 1. ADuCRF101 Block Diagram

Rev. PrG

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TABLE OF CONTENTS

Features	1	ESD Caution.....	9
Functional block diagram.....	1	Pin Configuration and Function Descriptions.....	10
General Description	3	Outline Dimensions	13
Specifications.....	4	Ordering Guide	13
Absolute Maximum Ratings.....	9		

GENERAL DESCRIPTION

The ADuCRF101 is a fully integrated data acquisition solution designed for low power wireless applications. It features a 12-bit or 14-bit ADC, a low power Cortex™-M3 processor from ARM®, a 431 MHz to 464 MHz and 862 MHz to 928 MHz RF transceiver, and Flash/EE memory packaged in a 9 mm × 9 mm LFCSP.

The acquisition section consists of a 12-bit / 14-bit ADC SAR ADC. The six inputs can be configured as single ended or differential modes. When configured in single ended mode, they can be used for ratiometric measurements on sensors, powered when required from the internal LDO. An internal battery monitor channel and an on-chip temperature sensor are also available.

This wireless data acquisition system is designed to operate in battery-powered applications where low power is critical. The device can be configured in normal operating mode or different low power modes under direct program control. In flexi mode any peripheral can operate and wake-up the device. In hibernate mode the internal wake-up timer remains active. In shutdown mode only an external interrupt can wake-up the device.

The ADuCRF101 integrates a low power Cortex-M3 processor from ARM. It is a 32-bit RISC machine, offering up to 1.25 DMIPS peak performance. The Cortex-M3 processor also has a flexible 14-channel DMA controller supporting communication peripherals SPI, UART and I²C. 64 kB / 128 kB of nonvolatile Flash/EE memory and 8 kB / 16 kB of SRAM are also provided on-chip.

A 16 MHz on-chip oscillator generates the system clock. This clock can be internally divided for the processor to operate at lower frequency for power saving reasons. A low power internal 32 kHz oscillator is available and can be used to clock the timers. There are two general-purpose timers, a wake-up timer and a system watchdog timer.

A range of communication peripherals can be configured as required in a specific application. These peripherals include UART, I²C, SPI, GPIO ports, PWM and RF transceiver.

The RF transceiver communicates in the 431 MHz to 464 MHz and 862 MHz to 928 MHz frequency bands using multiple configurations.

On-chip factory firmware supports in-circuit serial download via the UART while nonintrusive emulation and program download is also supported via the serial wire interface. These features are incorporated into a low cost development system supporting this precision analog microcontroller family.

The parts operate from 2.2 V to 3.6 V and are specified over an industrial temperature range of -40°C to +85°C.

Three versions of the ADuCRF101 are available:

- 14-bit ADC, 128 k Byte Flash and 16 k Byte SRAM
- 12-bit ADC, 128 k Byte Flash and 16 k Byte SRAM
- 12-bit ADC, 64 k Byte Flash and 8 k Byte SRAM

SPECIFICATIONS

ELECTRICAL SPECIFICATIONS

AVDD = IOVDD = VDDBAT1 = VDDBAT2 = 2.2 V to 3.6 V, $V_{REF} = 1.25$ V internal reference, $f_{CORE} = 16$ MHz, $T_A = -40^{\circ}\text{C}$ to $+85^{\circ}\text{C}$ unless otherwise noted. Default ADC sampling frequency: eight acquisition clocks and ADC clock frequency of 4 MHz.

Table 1. 12 Bit ADC channel specification

Parameter	Test Conditions / Comments	Min	Typ	Max	Unit
DC ACCURACY	Single ended input mode. Applies to all ADC input channels.				
Resolution			12		Bits
Integral Nonlinearity	$V_{REF} = 1.25$ V from internal reference		± 1		LSB
	$V_{REF} = 1.8$ V from LDO		± 2		LSB
Differential Nonlinearity	Guaranteed no missing code		± 1		LSB
DC Code Distribution	ADC input is a DC voltage		2		LSB
CALIBRATED ENDPOINT ERRORS	Measured using the factory-set default values ADCOF and ADCGN.				
Offset Error			± 0.6		LSB
Offset Error Match			± 0.25		LSB
Gain Error			± 1.25		LSB
Gain Error Match			± 0.25		LSB
DYNAMIC PERFORMANCE	$f_{IN} = 10$ kHz sine wave.				
Signal-to-Noise Ratio (SNR)			68		dB
Total Harmonic Distortion			TBD		
Peak Harmonic or Spurious Noise (PHSN)			TBD		
Channel-to-Channel Crosstalk	Measured on adjacent channels		TBD		

Table 2. 14 Bit ADC channel specification

Parameter	Test Conditions/Comments	Min	Typ	Max	Unit
ADC SPECIFICATIONS					
DC ACCURACY	Single ended input mode. Applies to all ADC input channels.				
Resolution			14		Bits
Integral Nonlinearity	$V_{REF} = 1.25$ V from internal reference		± 4		LSB
	$V_{REF} = 1.8$ V from LDO		± 8		LSB
Differential Nonlinearity	Guaranteed no missing code		± 1		LSB
DC Code Distribution	ADC input is a DC voltage		8		LSB
CALIBRATED ENDPOINT ERRORS	Measured using the factory-set default values ADCOF and ADCGN.				
Offset Error			± 2.5		LSB
Offset Error Match			± 1		LSB
Gain Error			± 5		LSB
Gain Error Match			± 1		LSB
DYNAMIC PERFORMANCE	$f_{IN} = 10$ kHz sine wave.				
Signal-to-Noise Ratio (SNR)			80		dB
Total Harmonic Distortion			TBD		
Peak Harmonic or Spurious Noise (PHSN)			TBD		
Channel-to-Channel Crosstalk	Measured on adjacent channels		TBD		

Table 3. ADuCRF101 Specification

Parameter	Test Conditions/Comments	Min	Typ	Max	Unit
ADC SPECIFICATIONS					
ANALOG INPUT					
Input Voltage Ranges ¹					
Single ended input		0		V_{REF}	V
Differential input		0		$V_{CM} \pm V_{REF}/2$	V
Leakage Current			100		nA
Input Capacitance	During ADC Acquisition		20		pF
ADC Power-up Time	Excludes reference power up time		5		μs
ON-CHIP VOLTAGE REFERENCE					
Output Voltage			1.25		V
Accuracy	Measured at $T_A = 25^\circ\text{C}$		±5		mV
Reference Temperature Co			±40		ppm/°C
Power Supply Rejection Ratio			60		dB
Output Impedance			2		Ω
Internal V_{REF} Power-On Time	0.47 μF external capacitor		5		ms
TEMPERATURE SENSOR¹					
Voltage Output at 25°C	Indicates die temperature		TBD		mV
Voltage TC			TBD		mV/°C
Accuracy	MCU in low power mode		TBD		°C
Thermal impedance			TBD		
CURRENT CONSUMPTION					
Cortex in SHUTDOWN mode	RF transceiver in sleep mode, memory not retained Wake up timer running from external 32 kHz crystal, 8 kB of SRAM retained (8 kB non-retained)		680		nA
Cortex in HIBERNATE mode					
RF transceiver in sleep mode, memory retained			1.6		μA
RF transceiver in sleep mode, memory not retained			1.38		μA
RF transceiver in receive mode			12.8		mA
RF transceiver in transmit mode			9 to 32		mA
Cortex in ACTIVE mode	RF transceiver idle (PHY_ON or PHY_OFF)				
Static current			1.8		mA
Dynamic current			190		μA/MHz
STARTUP TIME¹					
From Power On and SHUTDOWN mode	From applying power/asserting active external interrupt to user code execution FCLK is the Cortex-M3 clock or divided version of the 16 MHz oscillator.		50		ms
From FLEXI mode	From wake up event to user code execution		3 to 5		FCLK
From HIBERNATE mode	Includes 310 μs for 26 MHz crystal start up (7 pF load capacitor at $T_A = 25^\circ\text{C}$)		12.5		μs
RF link waking up from sleep mode			562.8		μs
POWER SUPPLY REQUIREMENTS					
Power Supply Voltage Range ¹		2.2		3.6	V
POWER SUPPLY MONITOR					
Trip Point voltage			2		V
POWER-ON-RESET					
Watchdog Timer ¹			1.67		V
Timeout Period	Programmable	0		512	S

Parameter	Test Conditions/Comments	Min	Typ	Max	Unit
Flash/EE MEMORY ¹ Endurance ² Data Retention ³	$T_J = 85^\circ\text{C}$	20,000 10			Cycles Years
Digital Inputs Input Current (leakage current) Input Capacitance	All digital inputs, excluding LFX TAL1 and XOSC26P $V_{\text{INH}} = \text{IOVDD}$ or $V_{\text{INH}} = 2.2\text{V}$, pull up disabled. $V_{\text{INL}} = 0\text{V}$, pull up disabled.		10 10		nA pF
Logic Inputs VINL, Input Low Voltage VINH, Input High Voltage	All Logic inputs, including LFX TAL1, excluding XOSC26P	0.7 x IOVDD		0.2 x IOVDD	V V
Logic Outputs VOH, Output High Voltage VOL, Output Low Voltage	$I_{\text{source}} = 1\text{ mA}$ $I_{\text{sink}} = 1\text{ mA}$	IOVDD - 0.4		0.36	V V
32.768 kHz CRYSTAL Input Current (leakage current) LFX TAL1 Input Capacitance LFX TAL2 Output Capacitance	32.768 kHz crystal, for use with timers and/or RF transceiver wake up controller. $V_{\text{INH}} = \text{IOVDD}$ or $V_{\text{INH}} = 2.2\text{ V}$ $V_{\text{INL}} = 0\text{ V}$.		50 2 2		nA pF pF
26 MHz CRYSTAL XOSC26P Input Capacitance XOSC26N Output Capacitance			10 10		pF pF
INTERNAL HF OSCILLATOR Tolerance	Processor clock by default		16 ± 3		MHz %
INTERNAL LF OSCILLATOR Tolerance			32.768 ± 20		kHz %
MCU CLOCK DIVIDER ¹	8 programmable core clock dividers.	1		128	
EXTERNAL CLOCK INPUT1 Range	External MCU clock range allowed	32.768		16000	kHz
RF LINK SPECIFICATIONS					
FREQUENCY RANGE		862 431		928 464	MHz MHz
PHASE-LOCKED LOOP Channel Frequency Resolution Phase Noise (In-Band)	10 kHz offset, PA output power = 10 dBm		396.7 -88		Hz dBc/Hz
DATA RATE 2FSK OOK Data rate resolution	Manchester Encoding enabled (Manchester chip rate = 2 x datarate)	1 2.4		300 19.2	kbps kbps bps
DIFFERENTIAL PA Transmit Power ⁴ Transmit Power variation V's Temperature Transmit Power Flatness	Programmable. From -40°C to $+85^\circ\text{C}$, RF Frequency = 868 MHz From 902 MHz to 928 MHz and 863 MHz to 870 MHz		-17 to 10 ± 1 ± 1		dBm dB dB
SINGLE ENDED PA Transmit Power ⁴	Programmable.		-21 to 13		dBm

Parameter	Test Conditions/Comments	Min	Typ	Max	Unit
Transmit Power variation V's Temperature	From -40°C to +85°C, RF Frequency = 868 MHz		±0.5		dB
Transmit Power Flatness	From 431 MHz to 464 MHz and 862 MHz to 928 MHz		±1		dB
HARMONICS	868 MHz, unfiltered conductive, PA output power = 10 dBm				
Differential PA					
Second Harmonic			TBD		dBc
Third Harmonic			TBD		dBc
All Other Harmonics			TBD		dBc
OPTIMUM PA LOAD IMPEDANCE					
Single-Ended PA, in Transmit Mode					
f _{RF} = 915 MHz			31.2+j10.4		Ω
f _{RF} = 868 MHz			23.5+j9.7		Ω
f _{RF} = 433 MHz			35.4+j3.4		Ω
Differential PA, in Transmit Mode	Load impedance between RFIO_1P and RFIO_1N to ensure maximum output power				
f _{RF} = 915 MHz			38.7+j20.6		Ω
f _{RF} = 868 MHz			42.2+j20.1		Ω
f _{RF} = 433 MHz			55.6+j54.9		Ω
MODULATION					
Deviation Frequency Resolution			100		Hz
2FSK/GFSK INPUT SENSITIVITY, BIT ERROR RATE (BER)	At BER = 10 ⁻³				
1.0 kbps	Frequency deviation = 10 kHz, IF filter bandwidth = 100 kHz		-116		dBm
38.4 kbps	Frequency deviation = 19.2 kHz, IF filter bandwidth = 100 kHz		-107.5		dBm
300 kbps	Frequency deviation = 75 kHz, IF filter bandwidth = 300 kHz		-100.5		dBm
2FSK/GFSK INPUT SENSITIVITY, PACKET ERROR RATE (PER)	At PER = 1%, packet length = 20 bytes, packet mode				
1.0 kbps	Frequency deviation = 10 kHz, IF filter bandwidth = 100 kHz		-115.5		dBm
38.4 kbps	Frequency deviation = 19.2 kHz, IF filter bandwidth = 100 kHz		-106		dBm
300 kbps	Frequency deviation = 75 kHz, IF filter bandwidth = 300 kHz		-98		dBm
ADJACENT CHANNEL REJECTION					
CW Interferer	Wanted signal 3 dB above the input sensitivity level (BER = 10 ⁻³), CW interferer power level increased until BER = 10 ⁻³ , image calibrated				
200 kHz Channel Spacing	IF BW = 100 kHz, wanted signal: F _{DEV} = 12.5 kHz, DR = 50 kbps		38		dB
300 kHz Channel Spacing	IF BW = 100 kHz, wanted signal: F _{DEV} = 25 kHz, DR = 100 kbps		39		dB
600 kHz Channel Spacing	IF BW = 300 kHz, wanted signal: F _{DEV} = 75 kHz, DR = 300 kbps		41		dB
Modulated Interferer	Wanted signal 3 dB above the input sensitivity level (BER = 10 ⁻³), modulated interferer with the same modulation as the wanted signal; interferer power level increased until BER = 10 ⁻³ , image calibrated				
200 kHz Channel Spacing	IF BW = 100 kHz, wanted signal: F _{DEV} =		38		dB

Parameter	Test Conditions/Comments	Min	Typ	Max	Unit
300 kHz Channel Spacing	12.5 kHz, DR = 50 kbps IF BW = 100 kHz, wanted signal: $F_{DEV} = 25$ kHz, DR = 100 kbps		36		dB
600 kHz Channel Spacing	IF BW = 300 kHz, wanted signal: $F_{DEV} = 75$ kHz, DR = 300 kbps		35		dB
CO-CHANNEL REJECTION	Desired signal 10 dB above the input sensitivity level ($BER = 10^{-3}$), data rate = 38.4 kbps, frequency deviation = 20 kHz.		-4		dB
BLOCKING, ETSI EN 300 220	Measurement procedure as per ETSI EN 300 220-1 V2.3.1; desired signal 3 dB above the ETSI EN 300 220 reference sensitivity level of -99 dBm, IF bandwidth = 100 kHz, data rate = 38.4 kbps, unmodulated interferer.				
±2 MHz			-28		dBm
±10 MHz			-20.5		dBm
WIDEBAND INTERFERENCE REJECTION	Swept from 10 MHz to 100 MHz either side of the RF frequency		75		dB
IMAGE CHANNEL ATTENUATION	Measured as image attenuation at the IF filter output, carrier wave interferer at 400 kHz below the channel frequency, 100 kHz IF filter bandwidth Uncalibrated ⁵ /calibrated				
868 MHz RSSI Range at Input			36/45		dB
Linearity			-97 to -26		dBm
Absolute Accuracy			±2 ±3		dB
LNA INPUT IMPEDANCE					
Receive Mode					
$f_{RF} = 915$ MHz			68.9-j36.1		Ω
$f_{RF} = 868$ MHz			71.6-j36.4		Ω
$f_{RF} = 433$ MHz			99.2-j31.3		Ω
Transmit Mode					
$f_{RF} = 915$ MHz			8.6+j21.1		Ω
$f_{RF} = 868$ MHz			8.6+j20.4		Ω
$f_{RF} = 433$ MHz			8.2+j11.4		Ω
RX SPURIOUS EMISSIONS					
Maximum <1 GHz	At antenna input, unfiltered conductive		TBD		dBm
Maximum >1 GHz	At antenna input, unfiltered conductive		TBD		dBm

¹ These numbers are not production tested, but are guaranteed by design and/or characterization data at production release.

² Endurance is qualified to 20,000 cycles as per JEDEC Std. 22 Method A117 and measured at -40°C, +25°C, and +85°C. Typical endurance at 25°C is 170,000 cycles.

³ Retention lifetime equivalent at a junction temperature (T_j) of 85°C as per JEDEC Std. 22 Method A117. Retention lifetime derates with junction temperature.

⁴ Measured as the maximum unmodulated power.

⁵ Measured with IMAGE_REJECT_CAL_AMPLITUDE = 0x7 and IMAGE_REJECT_CAL_PHASE = 0x16.

ABSOLUTE MAXIMUM RATINGS

T_A = 25°C unless otherwise noted

Table 4.

Parameter	Rating
AVDD, IOVDD, VDDBAT1 and VDDBAT2 to GND	-0.3 V to 3.96 V
Digital Input Voltage to GND	-0.3 V to 3.96 V
Digital Output Voltage to GND	-0.3 V to 3.96 V
V _{REF} to GROUND	-0.3 V to 3.96 V
Analog Inputs to GND	-0.3 V to 2.1 V
Operating Temperature Range	-40°C to +85°C
Storage Temperature Range	-65°C to +150°C
Junction Temperature	105°C
θ _{JA} Thermal Impedance	
64-Pin LFCSP _VQ	25°C/W
ESD (Human Body Model)	±1.5 kV
Peak Solder Reflow Temperature	
Pb-Free Assemblies (30 s)	260°C

ESD CAUTION



ESD (electrostatic discharge) sensitive device. Charged devices and circuit boards can discharge without detection. Although this product features patented or proprietary protection circuitry, damage may occur on devices subjected to high energy ESD. Therefore, proper ESD precautions should be taken to avoid performance degradation or loss of functionality.

The exposed paddle of the LFCSP package should be connected to ground.

Stresses above those listed under Absolute Maximum Ratings may cause permanent damage to the device. This is a stress rating only; functional operation of the device at these or any other conditions above those indicated in the operational section of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

PIN CONFIGURATION AND FUNCTION DESCRIPTIONS

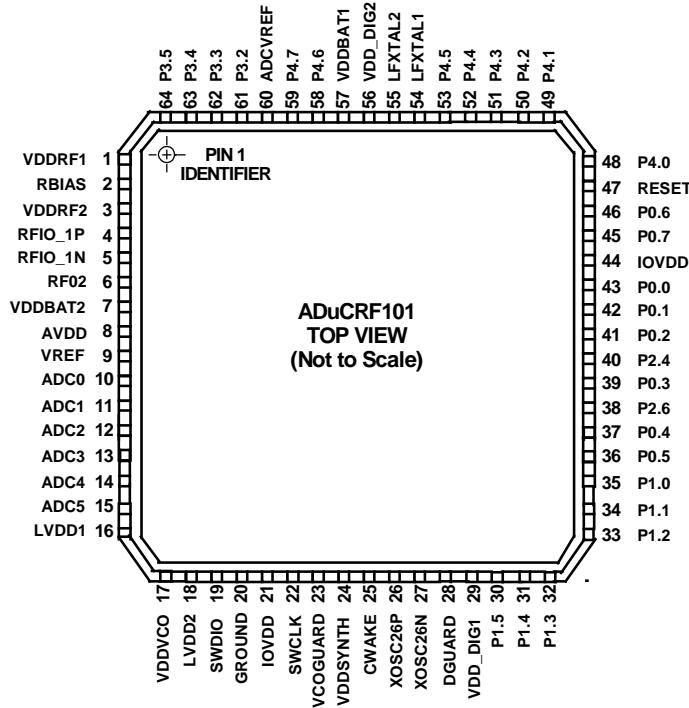


Figure 8. 64-Lead LFCSP_VQ Pin Configuration

Table 5. Pin Function Descriptions

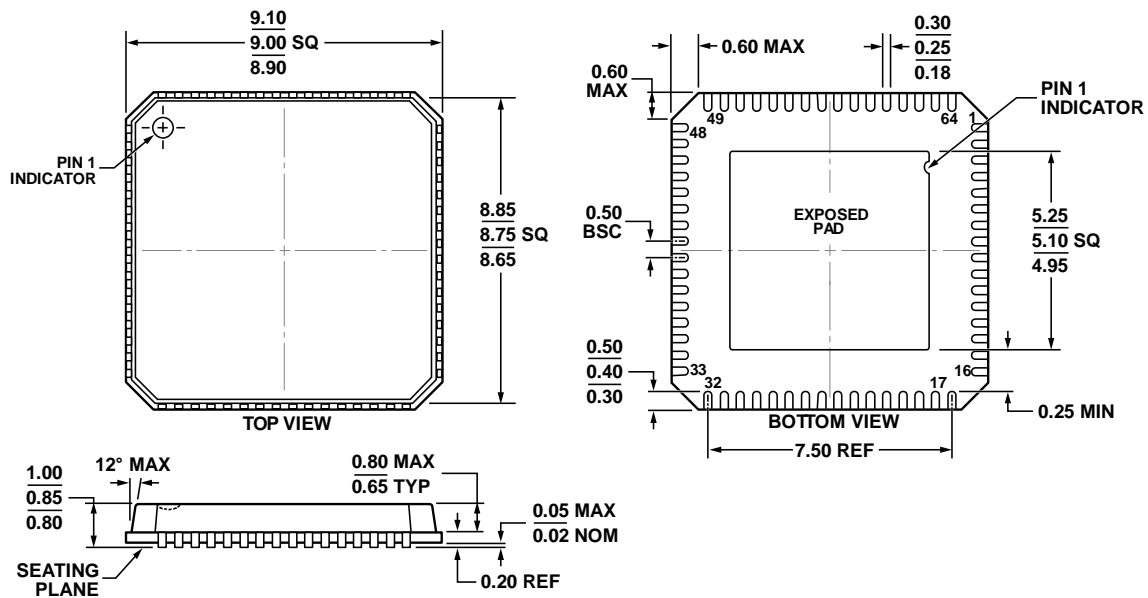
Pin No.	Mnemonic	Description
1	VDDRF1	Voltage Regulator output for RF block. A 220 nF capacitor should be placed between this pin and ground for regulator stability and noise rejection.
2	RBIAS	External bias resistor. A 36 kΩ resistor with 2% tolerance should be used.
3	VDDRF2	Voltage Regulator output for RF block. A 220 nF capacitor should be placed between this pin and ground for regulator stability and noise rejection.
4	RFIO_1P	LNA Positive Input in Receive Mode. Differential PA Positive Output in Transmit Mode.
5	RFIO_1N	LNA Negative Input in Receive Mode. Differential PA Negative Output in Transmit Mode.
6	RF02	Single ended PA output.
7	VDDBAT2 ⁶	Battery Terminal, supply for the LDOs used in the RF section of the transceiver.
8	AVDD ⁶	Battery terminal, Supply for analog circuits such as ADC and ADC internal reference, POR, PSM and LDOs.
9	VREF	Internal 1.25 V ADC reference. A 0.47 μF capacitor between this pin and ground is required.
10	ADC0	ADC input channel 0. Input of DIFF0 pair in differential mode.
11	ADC1	ADC input channel 1. Input of DIFF0 pair in differential mode.
12	ADC2	ADC input channel 2. Input of DIFF1 pair in differential mode.
13	ADC3	ADC input channel 3. Input of DIFF1 pair in differential mode.
14	ADC4	ADC input channel 4. Input of DIFF2 pair in differential mode.
15	ADC5	ADC input channel 5. Input of DIFF2 pair in differential mode.
16	LVDD1	On chip LDO decoupling output. Connect a 0.47 μF capacitor to the 1.8V output to ensure core operating voltage is stable. For correct operation a 1 μF capacitor needs to be connected between this pin and LVDD2 (pin 18).
17	VDDVCO	Voltage Regulator output for VCO. A 220 nF capacitor should be placed between this pin and ground for regulator stability and noise rejection.
18	LVDD2	On chip LDO decoupling output. Connect a 0.47 μF capacitor to the 1.32V output to ensure core operating voltage is stable. For correct operation a 1 μF capacitor needs to be connected between this pin and LVDD1 (pin 16).
19	SWDIO	Serial Wire bi-directional data

Pin No.	Mnemonic	Description
20	GND	Ground pin, should be connected to the PADDLE.
21	IOVDD ⁶	Battery terminal, General Purpose IO supply.
22	SWCLK	Serial Wire debug clock
23	VCOGUARD	Guard, screen for VCO, should be connected to VDDVCO.
24	VDDSYNTH	Voltage Regulator output for Synthesizer. A 220 nF capacitor should be placed between this pin and ground for regulator stability and noise rejection.
25	CWAKE	External capacitor for wake up control. A 150 nF capacitor should be placed between this pin and ground.
26	XOSC26P	The 26MHz reference crystal should be connected between this pin and XOSC26N. (HFXTAL)
27	XOSC26N	The 26MHz reference crystal should be connected between this pin and XOSC26P. (HFXTAL)
28	DGUARD	Internal Guard, Screen for Digital Cells, should be connected to VDD_DIG1.
29	VDD_DIG 1	Voltage Regulator output for Digital. A 220 nF capacitor should be placed between this pin and ground for regulator stability and noise rejection.
30	P1.5/IRQ6/I2CSDA/PWM7	General Purpose Input and Output Port 1.5/External Interrupt 6/I2C Serial Data/PWM channel 7.
31	P1.4/IRQ5/I2CSCL/PWM6	General Purpose Input and Output Port 1.4/External Interrupt 5/I2C Serial Clock/PWM channel 6.
32	P1.3/PWM5	General Purpose Input and Output Port 1.3/PWM channel 5.
33	P1.2/PWM4	General Purpose Input and Output Port 1.2/PWM channel 4.
34	P1.1/PORB/ TXD /PWM3	General Purpose Input and Output Port 1.1/POR output/ UART TXD/ PWM channel 3.
35	P1.0/RXD/IRQ4/MOSI /PWM2	General Purpose Input and Output Port 1.0/UART RXD/ External Interrupt 4/ SPI1 Master Out Slave In Pin (MOSI)/PWM channel 2.
36	P0.5/ $\overline{CS2}$ /ECLKIN	General Purpose Input and Output Port 0.5/SPI1 Chip Select 2/External Clock Input
37	P0.4/ $\overline{CS1}$ /ECLKOUT	General Purpose Input and Output Port 0.4/SPI1 Chip Select 1/External Clock Output.
38	P2.6	General Purpose Input and Output Port 2.6. This pin should not be connected. This pin is connected internally to the RF transceiver. It can be used for BER measurements.
39	P0.3/IRQ1/ $\overline{CS0}$ /ADCCONVST/PWM1	General Purpose Input and Output Port 0.3/External Interrupt 1/SPI1 Chip Select 0/ADC convert start/PWM channel 1.
40	P2.4/IRQ8	General Purpose Input and Output Port 2.4. This pin should not be connected. This pin is connected internally to the RF transceiver. It can be used for debug purposes to monitor RF transceiver interrupt/ External Interrupt 8
41	P0.2/MOSI/PWM0	General Purpose Input and Output Port 0.2/SPI1 Master Out Slave In Pin (MOSI)/PWM channel 0.
42	P0.1/SCLK	General Purpose Input and Output Port 0.1/SPI1 Serial Clock
43	P0.0/MISO	General Purpose Input and Output Port 0.0/SPI1 Master In Slave Out Pin (MISO)
44	IOVDD	General Purpose I/O supply. Connect to the battery terminal
45	P0.7/IRQ3/ $\overline{CS4}$ /CTS	General Purpose Input and Output Port 0.7/ External Interrupt 3 / SPI1 Chip Select 4/ UART hand shake.
46	BM/P0.6/IRQ2/ $\overline{CS3}$ /RTS/PWM0	BM (Boot Mode). The ADuCRF101 enters serial download mode if P0.6 is low during an external Reset event. It executes user code after any reset event or if P0.6 is high during an external Reset event. / General Purpose Input and Output Port 0.6/External Interrupt 2/ SPI1 Chip Select 3 / UART hand shake/PWM channel 0.
47	RESET	Active Low. A low signal on this pin for 24 system clocks will cause the part to reset.
48	P4.0/PWM0	General Purpose Input and Output Port 4.0/PWM channel 0.
49	P4.1/PWM1	General Purpose Input and Output Port 4.1/PWM channel 1.
50	P4.2/PWM2	General Purpose Input and Output Port 4.2/PWM channel 2.
51	P4.3/PWM3	General Purpose Input and Output Port 4.3/PWM channel 3.
52	P4.4/PWM4	General Purpose Input and Output Port 4.4/PWM channel 4.
53	P4.5/PWM5	General Purpose Input and Output Port 4.5/PWM channel 5.
54	LFXTAL1	32.768 kHz watch crystal output for WU timers.
55	LFXTAL2	32.768 kHz watch crystal input for WU timers.
56	VDD_DIG2	Voltage Regulator output for Digital section of the transceiver. A 220 nF capacitor should be placed between this pin and ground for regulator stability and noise rejection.
57	VDDBAT1 ⁶	Battery Terminal, supply for the digital section of the transceiver and GPIOs.
58	P4.6/PWM6	General Purpose Input and Output Port 4.6/PWM channel 6.
59	P4.7/PWM7	General Purpose Input and Output Port 4.7/PWM channel 7.

Pin No.	Mnemonic	Description
60	ADCVREF	Transceiver's ADC Reference Output. A 220 nF capacitor should be placed between this pin and ground for adequate noise rejection.
61	P3.2/PWMSYNC	General Purpose Input and Output Port 3.2/PWM synchronisation.
62	P3.3/PWMTRIP	General Purpose Input and Output Port 3.3/PWM safety cut off.
63	P3.4	General Purpose Input and Output Port 3.4.
64	P3.5	General Purpose Input and Output Port 3.5.
65	PADDLE	The exposed package paddle should be soldered to a metal pad on the PCB, and connected to ground.

⁶ VDDBAT1, VDDBAT2, AVDD and IOVDD should all be connected together.

OUTLINE DIMENSIONS



COMPLIANT TO JEDEC STANDARDS MO-220-VMMD-4

Figure 2. 64-Lead Frame Chip Scale Package [LFCSP_VQ]
9 mm x 9 mm Body, Very Thin Quad
(CP-64-5)
Dimensions shown in millimeters

06-14-2012-A

ORDERING GUIDE

Model	Temperature Range	Description	Package Option
ADUCRF101BCPZ64	-40°C to 85°C	12-bit ADC, 164k Byte Flash and 8k Byte SRAM	64-lead LFCSP
ADUCRF101BCPZ128	-40°C to 85°C	12-bit ADC, 128k Byte Flash and 16k Byte SRAM	64-lead LFCSP
ADUCRF101CCPZ128	-40°C to 85°C	14-bit ADC, 128k Byte Flash and 16k Byte SRAM	64-lead LFCSP
EV-ADuCRF101MK3Z	-40°C to 85°C	Evaluation board for 433 MHz operation	N/A
EV-ADuCRF101MK1Z	-40°C to 85°C	Evaluation board for 915 MHz operation	N/A
EV-ADuCRF101QSP1Z	-40°C to 85°C	Quick start Plus for 915 MHz operation	N/A
EV-ADuCRF101QSP3Z	-40°C to 85°C	Quick start Plus for 433 MHz operation	N/A

I²C refers to a communications protocol originally developed by Philips Semiconductors (now NXP Semiconductors).